

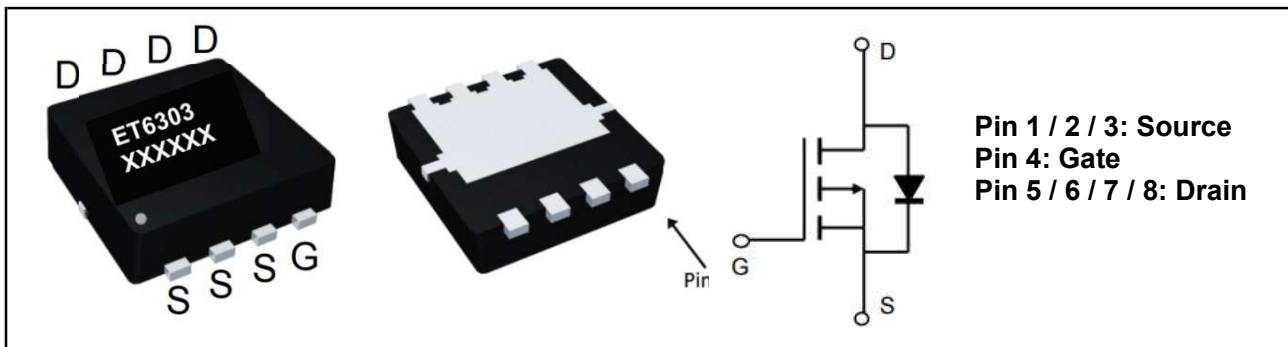
### P-Channel Enhancement-Mode MOSFET (-30V, -50A)

#### PRODUCT SUMMARY

$V_{DS}$	$I_D$	$R_{DS(on)}$ (m $\Omega$ ) Typ.
-30V	-50A	7.5 @ $V_{GS} = 10V, I_D=20A$
		11 @ $V_{GS} = 4.5V, I_D=10A$

#### Features

- Super high density cell design for extremely low RDS(ON)
- Exceptional on-resistance and maximum DC current capability
- Fast Switching
- Lead (Pb) -free and halogen-free



#### Absolute Maximum Ratings ( $T_A=25^{\circ}C$ , unless otherwise noted)

Symbol	Parameter	Ratings	Units
$V_{DS}$	Drain-Source Voltage	-30	V
$V_{GS}$	Gate-Source Voltage	$\pm 20$	V
$I_D$	Drain Current (Continuous)@ $T_A=25^{\circ}C$	-50	A
	Drain Current (Continuous)@ $T_A=75^{\circ}C$	-30	A
$I_{DM}$	Drain Current (Pulsed) <sup>a</sup>	-188	A
$P_D$	Total Power Dissipation @ $T_C=25^{\circ}C$	38	W
	Total Power Dissipation @ $T_C=75^{\circ}C$	22	W
$I_S$	Maximum Diode Forward Current	-47	A
$T_J, T_{stg}$	Operating Junction and Storage Temperature Range	-55 to +150	$^{\circ}C$
$R_{QJA}$	Thermal Resistance Junction to Ambient (PCB mounted) <sup>b</sup>	35	$^{\circ}C/W$

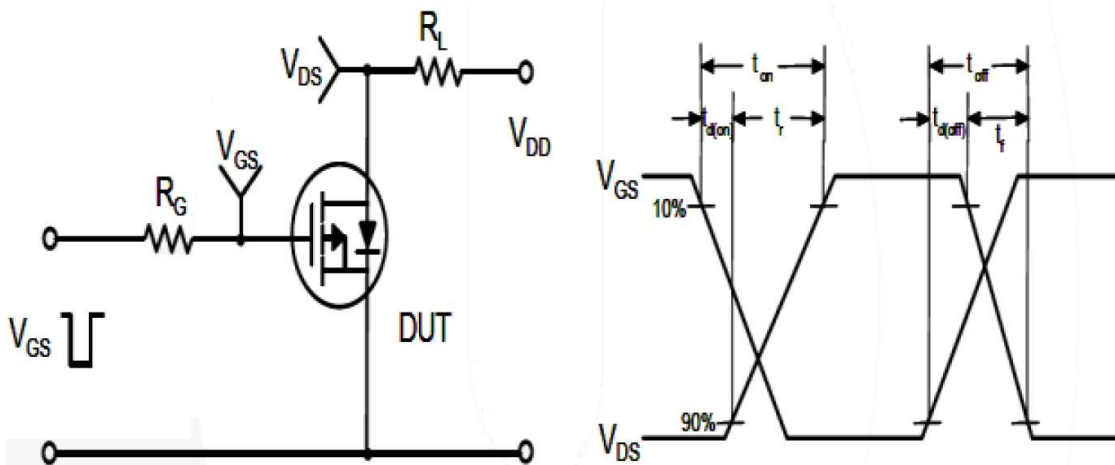
a: Repetitive Rating: Pulse width limited by the maximum junction temperature.

b: 1-in<sup>2</sup> 2oz Cu PCB board

### Electrical Characteristics (T<sub>A</sub>=25°C, unless otherwise noted)

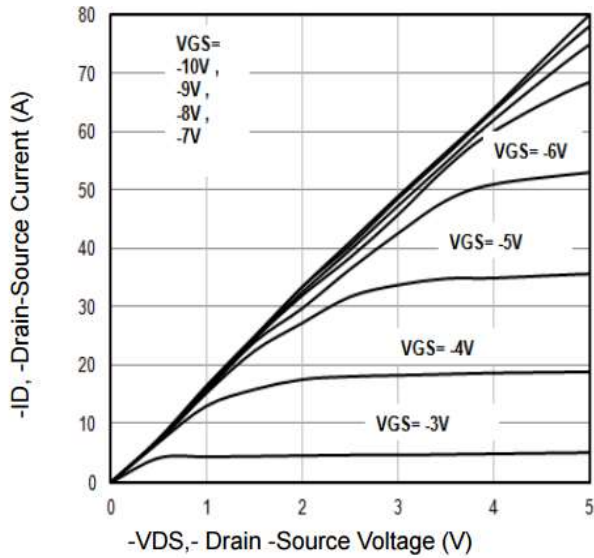
Symbol	Characteristic	Test Conditions	Min.	Typ.	Max.	Unit
<b>• Off Characteristics</b>						
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V, I <sub>D</sub> =-250uA	-30	-	-	V
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> =30V, V <sub>GS</sub> =0V	-	-	1	μA
I <sub>GSS</sub>	Gate-Body Leakage Current	V <sub>GS</sub> =±20V, V <sub>DS</sub> =0V	-	-	±100	nA
<b>• On Characteristics</b>						
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> =250uA	-1.0	-1.4	-2.0	V
R <sub>DS(on)</sub>	Drain-Source On-State Resistance	V <sub>GS</sub> =-10V, I <sub>D</sub> =-20A	-	7.5	11	mΩ
		V <sub>GS</sub> =-4.5V, I <sub>D</sub> =-16A	-	11	20	
<b>• Dynamic Characteristics</b>						
C <sub>iss</sub>	Input Capacitance	V <sub>DS</sub> =-15V, V <sub>GS</sub> =0V, f=1MHz	-	3320	-	PF
C <sub>oss</sub>	Output Capacitance		-	395	-	
C <sub>rss</sub>	Reverse Transfer Capacitance		-	245	-	
<b>• Switching Characteristics</b>						
Q <sub>g</sub>	Total Gate Charge	V <sub>DS</sub> =-15V, I <sub>D</sub> =20A, V <sub>GS</sub> =-10V	-	39	-	nC
Q <sub>gs</sub>	Gate-Source Charge		-	7	-	
Q <sub>gd</sub>	Gate-Drain Charge		-	11	-	
t <sub>d(on)</sub>	Turn-on Delay Time	V <sub>DD</sub> =15V, R <sub>L</sub> =15Ω, I <sub>D</sub> =20A, V <sub>GEN</sub> =10V, R <sub>G</sub> =6Ω	-	15	-	nS
t <sub>r</sub>	Turn-on Rise Time		-	33	-	
t <sub>d(off)</sub>	Turn-off Delay Time		-	67	-	
t <sub>f</sub>	Turn-off Fall Time		-	21	-	
<b>• Drain-Source Diode Characteristics</b>						
V <sub>SD</sub>	Drain-Source Diode Forward Voltage	V <sub>GS</sub> =0V, I <sub>S</sub> =20A	-	-	-1.2	V

Note: Pulse Test: Pulse Width ≤ 300us, Duty Cycle ≤ 2%

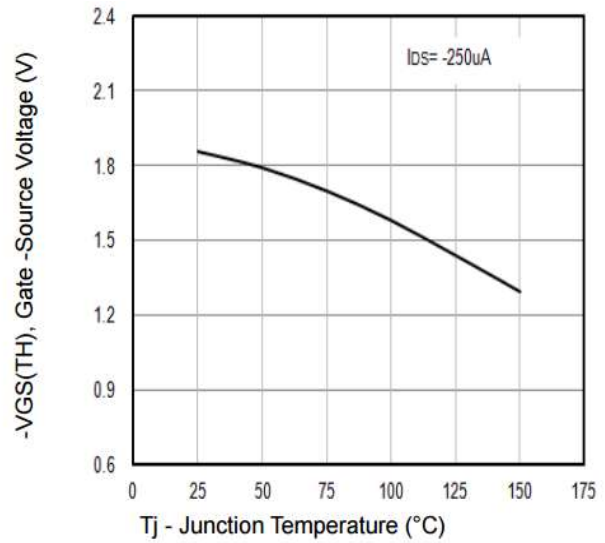


Switching Time Test Circuit and waveforms

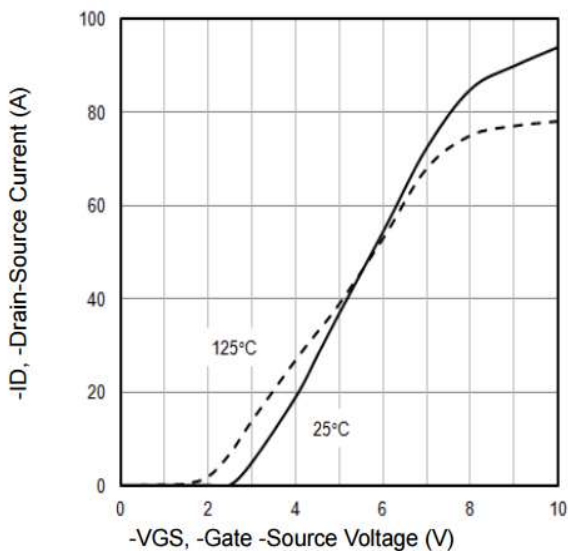
### Typical Characteristics Curves (Ta=25°C, unless otherwise note)



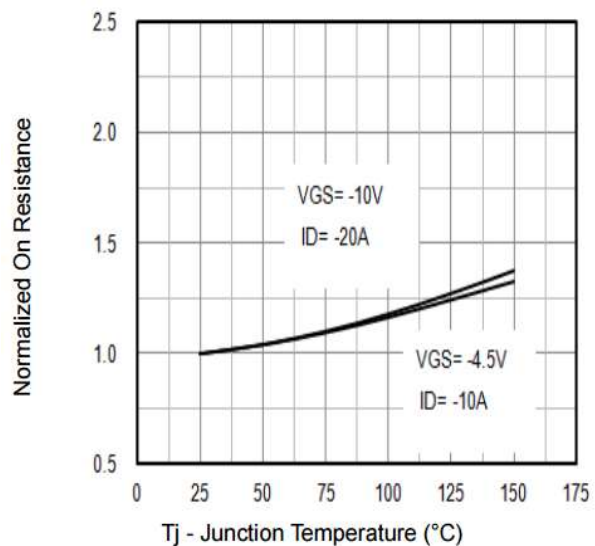
**Fig1.** Typical Output Characteristics



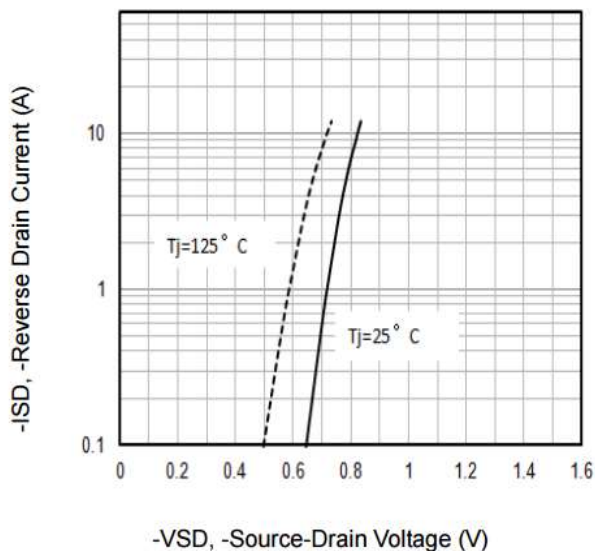
**Fig2.**  $-V_{GS(TH)}$  Gate-Source Voltage Vs.  $T_J$



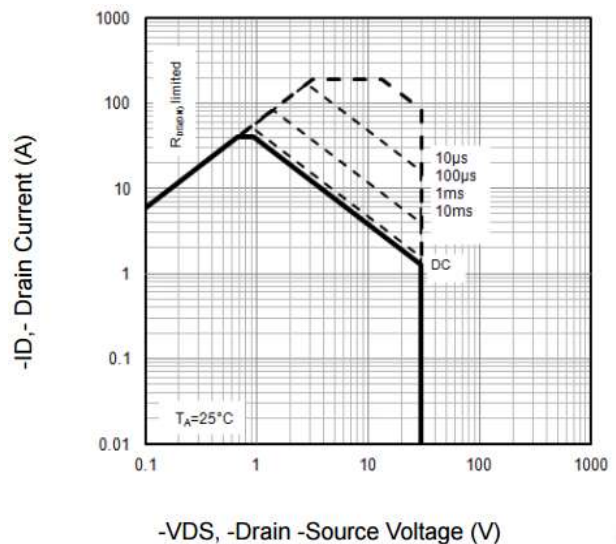
**Fig3.** Typical Transfer Characteristics



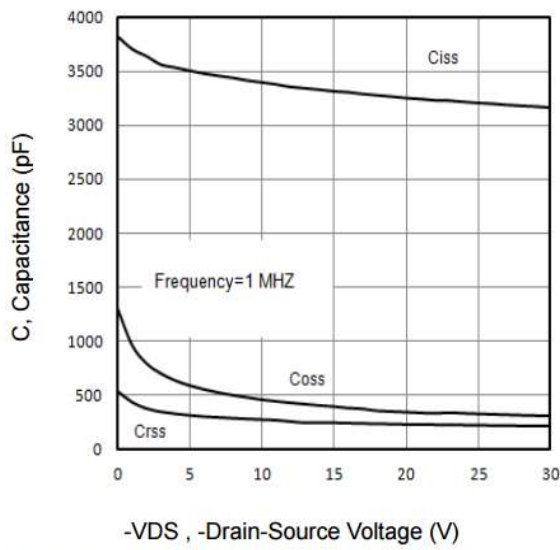
**Fig4.** Normalized On-Resistance Vs.  $T_J$



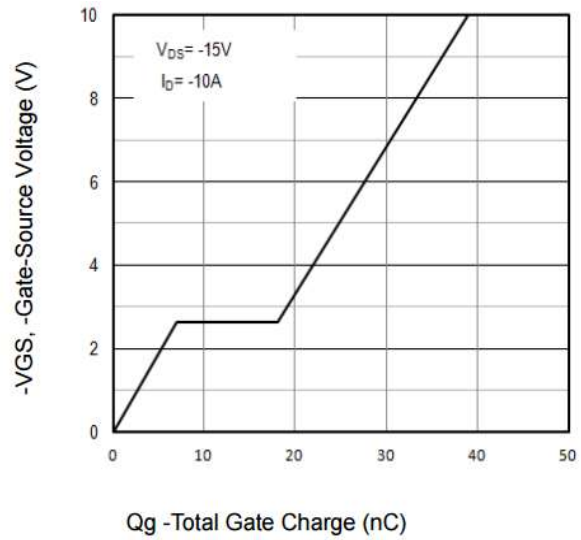
**Fig5.** Typical Source-Drain Diode Forward Voltage



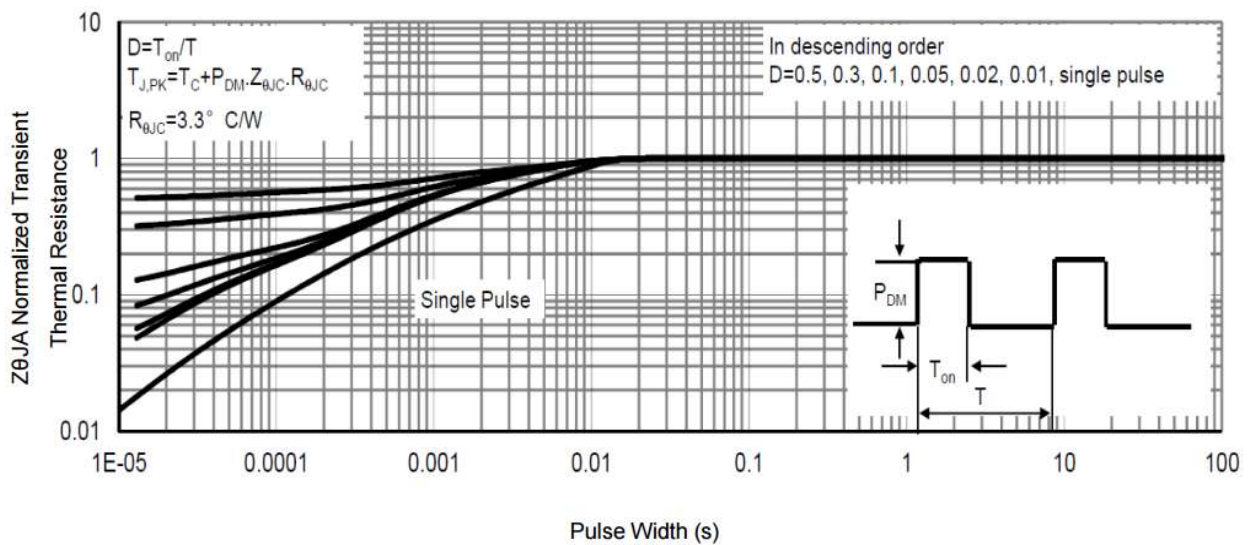
**Fig6.** Maximum Safe Operating Area



**Fig7.** Typical Capacitance Vs. Drain-Source Voltage

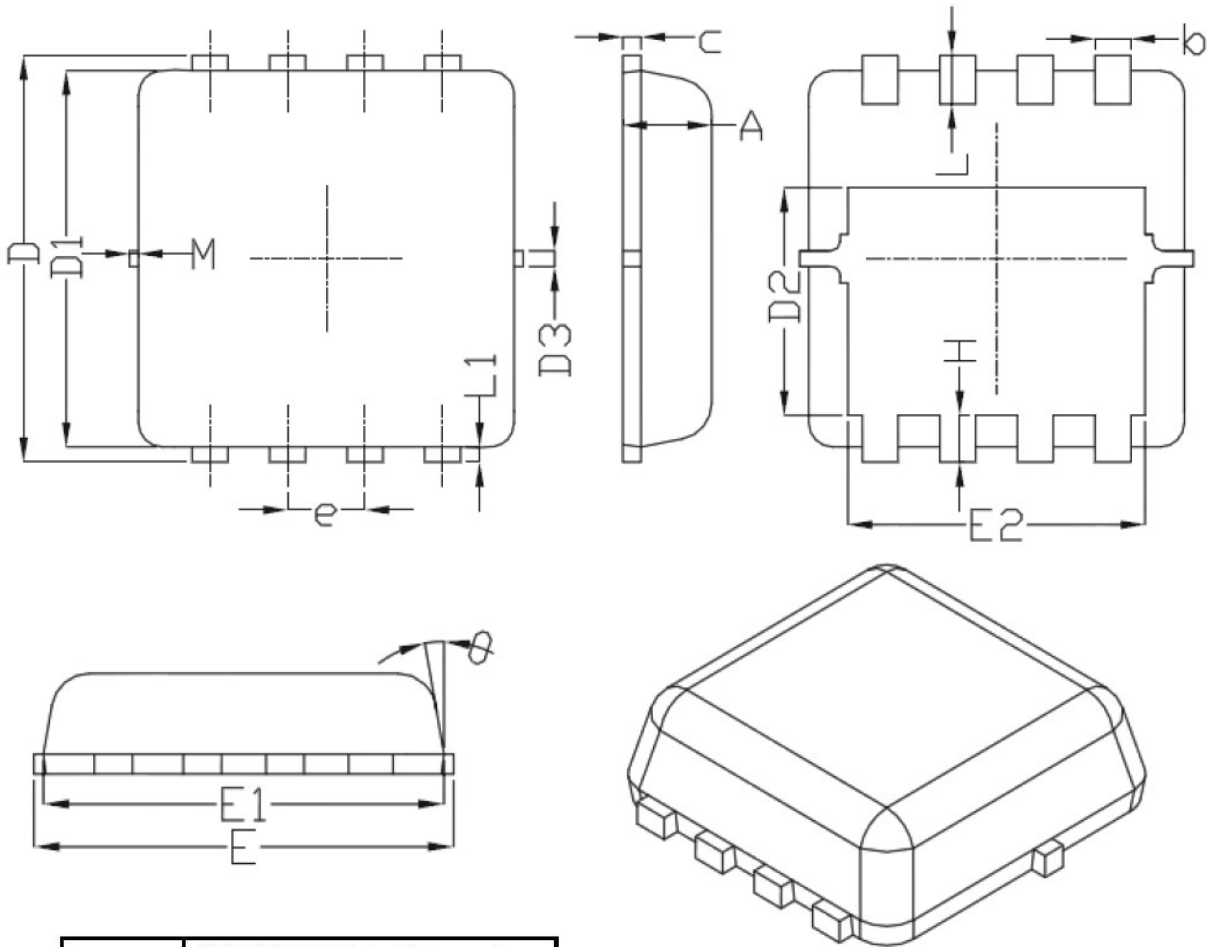


**Fig8.** Typical Gate Charge Vs. Gate-Source Voltage



**Fig9.** Normalized Maximum Transient Thermal Impedance

### PDFN3333 PACKAGE OUTLINE DIMENSIONS



Symbol	DIMENSIONS ( unit : mm )		
	Min	Typ	Max
A	0.7	0.75	0.8
b	0.25	0.3	0.35
C	0.1	0.15	0.25
D	3.25	3.35	3.45
D1	3	3.1	3.2
D2	1.78	1.88	1.98
D3	--	0.13	--
E	3.2	3.3	3.4
E1	3	3.15	3.2
E2	2.39	2.49	2.59
e	0.65 BSC		
H	0.3	0.39	0.5
L	0.3	0.4	0.5
L1	--	0.13	--
θ	--	10°	12°
M	*	*	0.15